
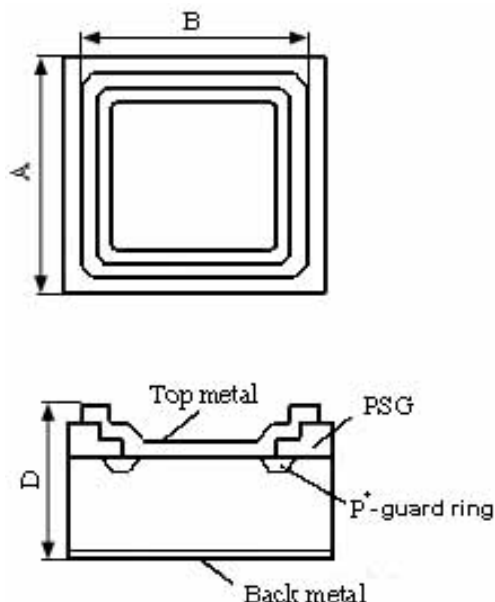


		0,5A/20V. Die Size-16mil.		
				
Electrical Characteristics	Symbol	Unit	Spec. limit	Die Sort
Breakdown Voltage @ $I_R=10\text{mA}$	V_{BR}	V	20	23
Average Rectified Forward Current	$I_{F(AV)}$	mA	500	-
DC Forward Voltage @ 25°C , $I_F=0,5\text{A}$	V_F	V	tbd	0,47
Maximum Reverse Current @ 25°C , $V_R=20\text{V}$ @ 125°C , $V_R=20\text{V}$	I_R	mA	0,05 10,0	0,03 8,0
Peak Forward Surge Current 8,3ms single half sine-wave superimposed on rated load (JEDEC METHOD)	I_{FSM}^*	A	5	-
Peak Repetitive Reverse Surge Current @ $2,0\mu\text{s}$, $f=1\text{kHz}$., $T_j<175^\circ\text{C}$.	I_{RRM}	A	0,5	
Electrostatic Discharge Voltage. JEDEC Method. ESD HBM. Contact.	V_{ESD}	kV	± 5 (contact)	
Voltage Rate of Change	dV/dt	$\text{V}/\mu\text{S}$	10.000	
Operating Junction Temperature	T_j^*	$^\circ\text{C}$	150	

* - testing for Device

* $T_j = T_a + R_{th(j-a)} \times (P_f + P_r)$, where $R_{th(j-a)}$ – thermal resistance, P_f – forward power dissipation, P_r – reverse power dissipation



Mechanical data

DIM	ITEM	μm
A_x A_y	Wafer Form Die Size	410 410
B_x B_y	Top Metal Size	310 310
D	Thickness	245max.
Scribe line Width		40

Top metal:

- a) **Al-Ni-Ag** – for Soldering;
- b) **Al** – for Wire Bonding.

Backside metal: **Ti-Ni-Ag**.